## Application/Control No. Applicant(s)/Patent Under Reexamination 10/603,438 SHAYLOR ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2192 J. Derek Rutten **U.S. PATENT DOCUMENTS**

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	К	US-			
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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